

IMEP-LAHC, UMR 5130**Equipe CMNE "Composants Micro-Nanoélectroniques"****Publications dans des conférences internationales avec actes (2010)**

Année	Auteurs	Titre		Sigle	Conférence	Lieu, date	Actes
2010	J.R. Ngankio-Njila, D-G. Crété, J-C. Mage, B. Marcilhac, and P. Febvre	Concept of Superconducting Pipeline A/D Converter		ASC	Applied Superconductivity Conference (ASC 2010)	Washington DC, August 1-6, 2010.	Contribution submitted to IEEE Transactions on Applied Superconductivity.
2010	I. Ionica, A. El Hajj Diab, Y.H. Bae, X. Mescot, A. Ohata, F. Allibert, S. Cristoloveanu	Advances in the pseudo-MOSFET characterization method	Invited paper	CAS	International Semiconductor Conference (CAS'2010)	Sinaia (Roumanie), Oct 2010	IEEE Conference Proceedings. Part vol.1, pp. 45-51 (2010)
2010	S. Cristoloveanu	SOI Promises for Speed, Energy and Memory.	Invited paper	COMMAD	2010 Conf. on Optoelectronic and Microelectronic Materials and Devices (COMMAD'10)	Canberra, Australie (12-15 dec. 2010)	Abstract booklet
2010	E. Rauwel, P. Rauwel, F. Ducroquet, I. Matko, A. Lourenço	Oxygen diffusion barrier applied to high-k thin films deposition		ECS Fall Meeting	218th ECS conf	Las Vegas, USA (10-15 Oct. 2010)	ECS transactions, Vol. 33, n°3, 497-506 (2010)
2010	D. Bauza	Charge pumping and Si-SiO ₂ interface traps electrical characterisation	Invited paper	ECS Spring Meeting	217th Meeting of the Electrochemical Soc., Dielectrics for Nanosystems III: Materials Science, Processing, Reliability, and Manufacturing	Vancouver, Canada (25-30 April 2009)	ECS Transactions vol. 28, n° 2, pp. 251-261, ISBN: 878-1-56677-782-6.
2010	F. Ducroquet, E. Rauwel, V. Brizé, C. Dubourdieu	Dielectric properties and flat-band voltages of doped HfO ₂ thin films	Invited paper	ECS Spring Meeting	217th ECS conf, Symp. E2, #E2-1104O	Vancouver, Canada 25-30 Avril 2010)	ECS transactions, Vol. 28, n°2, 191-202 (2010)
2010	M. Ollivier, A. Mantoux, E. Bano, K. Rogdakis, T. Baron, L. Latu-Romain	Growth of SiC microwires through Si microwires carburization		ECSCRM	European Conference on Silicon Carbide and Related Materials	Oslo, Norvège (Oct. 2010)	Materials Science Forum Vols. 679-680 (2011) pp 512-515
2010	K. Rogdakis, E. Bano, L. Montes, M. Bechelany, D. Cornu, K. Zekentes	Schottky barrier 3C-SiC nanowire field effect transistor		ECSCRM	European Conference on Silicon Carbide and Related Materials	Oslo (Norvège), Octobre 2010	Materials Science Forum Vols. 679-680 (2011) pp 613-616
2010	P.Gueguen, L. Di Cioccio, P. Morfouli, M. Zussy, J. Dechamp, L. Bally, L. Clavelier	Copper Direct Bonding: an innovative 3D interconnect		ECTC	59th Electronic Components and Technology Conference	Las Vegas, USA (14 June 2010)	
2010	L. Negre, D. Roy, S. Boret, P. Scheer, G. Ghibaud	From DC to RF MOSFET reliability (45nm).		EMW	13th European Microwave Week	Paris (sept 2010)	

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2010	L. Gerrer, M. Rafik, G. Ribes, G. Ghibaudo, E. Vincent	Unified Soft Breakdown MOSFETs Compact Model: From Experiments to Circuit Simulation		ESREF	21st European Symposium on Reliability of Electron Devices, Failure Physics and Analysis, ESREF 2010	Monte Cassino, Italy (Oct 2010)	
2010	R. Ritzenthaler, F. Lime, B. Iniguez, O. Faynot, S. Cristoloveanu	3D analytical modelling of subthreshold characteristics in Pi-gate FinFET transistors.		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	Proc. in ESSDERC 2010, (F. Gamiz, A. Godoy eds.), IEEE, ISBN 978-1-4244-6659-7, 448-451 (2010)
2010	K. Tachi, N. Vulliet, S. Barraud, B. Guillaumot, V. Maffini-Alvaro, C. Vizios, C. Arvet, Y. Campidelli, P. Gautier, J.M. Hartmann, T. Skotnicki, S. Cristoloveanu, H. Iwai, O. Favnot, T. Ernst	3D source/drain doping optimization in multi-channel MOSFET.		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	Proc. in ESSDERC 2010, (F. Gamiz, A. Godoy eds.), IEEE, ISBN 978-1-4244-6659-7, 368-371 (2010)
2010	C. M. Mezzomo, A. Bajolet, A. Cathignol and G. Ghibaudo	Drain Current Variability in 45nm Heavily Pocket-implanted Bulk MOSFET: Characterization and Modeling		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	
2010	J. W. Lee, D. Jang, M. Mouis, G. T. Kim, T. Chiarella, T. Hoffmann and G. Ghibaudo	Experimental Analysis of Surface Roughness Scattering in FinFET devices	Young scientist award	ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	IEEE Conference Proceedings pp 305-308 (Sept. 2010)
2010	A. Hubert, M. Bawedin, G. Guegan, S. Cristoloveanu, T. Ernst, O. Faynot	Experimental comparison of programming mechanisms in 1T-DRAM cells with variable channel length.		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	Proc. in ESSDERC 2010, (F. Gamiz, A. Godoy eds.), IEEE, ISBN 978-1-4244-6659-7, 150-153 (2010)
2010	N. Rodriguez, S. Cristoloveanu, F. Gamiz	Origins of universal mobility violation in SOI MOSFETs.		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	Proc. in ESSDERC 2010, (F. Gamiz, A. Godoy eds.), IEEE, ISBN 978-1-4244-6659-7, 420-423 (2010)
2010	Subramanian N, G. Ghibaudo, M. Mouis	Parameter Extraction of Nano-Scale MOSFETs Using Modified Y Function Method		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	IEEE Conference Proceedings pp 309-312 (Sept. 2010)
2010	J. Wan, C. Le Royer, A. Zaslavsky, S. Cristoloveanu	SOI TFETs : Suppression of ambipolar leakage and low-frequency noise behavior.		ESSDERC	40th European Solid-State Device Research Conference	Sevilla, Spain (13-17 sept. 2010)	Proc. in ESSDERC 2010, (F. Gamiz, A. Godoy eds.), IEEE, ISBN 978-1-4244-6659-7, 341-344 (2010)
2010	R. Ritzenthaler, M. Tang, O. Faynot, F. Lime, F. Pregaldiny, C. Lallement, S. Cristoloveanu, B. Iniguez	A 2D analytical model of threshold voltage for Pi-gate FinFET transistors.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet

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2010	B. Cousin, M. Reyboz, O. Rozeau, M.A. Jaud, T. Ernest and J. Jomaah	An Explicit Compact Model of Quantum-Mechanical Effects for Cylindrical Surrounding-Gate MOSFETs		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet, pp. 127-128
2010	N. Rodriguez, F. Gamiz, S. Cristoloveanu	Capacitor-less A-RAM memory cell : operation, scaling and expected performance.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet
2010	G. Ghibaudo	Electrical characterisation of SOI nanodevices	Invited paper	Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (Jan 2010)	Abstract booklet
2010	A. Ohata, S. Cristoloveanu	Evaluation of electrical characteristics in fully depleted SOI MOSFETs for variable threshold voltage scheme.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet
2010	W. Van Den Daele, C. Le Royer, J. Mitard, G. Ghibaudo, S. Cristoloveanu	Improved extraction of effective electric field and hole mobility in Ge and GeOI MOSFETs.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet
2010	C.D.G. Dos Santos, S. Cristoloveanu, D.K. Maude, J.A. Martino	Magnetoresistance technique for mobility extraction in triple gate FinFETs at low temperature.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet
2010	K-H. Park, S. Cristoloveanu, M. Bawedin, Y-H. Bae, K-I. Na, J-H. Lee	Partially depleted double-gate 1T-DRAM cell using nonvolatile memory function for improved performance.		Euro-SOI	6th Workshop of the Thematic Network on Silicon on Insulator technology, devices and circuits	Grenoble, France (25-27 janvier 2010)	Abstract booklet
2010	S. Altazin, R. Clerc, R. Gwoziecki, D. Boudinet, G. Ghibaudo, G. Pananakakis, I. Chartier, R. Coppard	Contact Resistance in Top Gate / Bottom Contact OTFTs.		ICOE	International Conference on Organic Electronics 2010	Paris, France (22-25 June 2010)	Sans
2010	Yong Xu, Gérard Ghibaudo, Francis Balestra, Jan Chroboczek, Romain Gwoziecki, Isabelle Chartier, Romain Coppard	Static and low frequency noise characterization of P-type polymer and N-type small molecule OFETs		ICOE	International Conference on Organic Electronics	Paris (22-25 June 2010)	

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2010	S. Tutashkonko, A. Kaminski-Cachopo, C. Boulord, R. Ares, V. Aimez and M. Lemiti	Copper light induced plating on silver screen-printed contacts of silicon solar cells		ICPSCG	IX International Conference of Polish Society for Crystal Growth - ICPSCG-9	Gdansk, Poland (23-27 May 2010)	Proceedings of the ICPSCG-9
2010	Pascal Febvre, Hèla Gassara, Patricia Desgreys and Patrick Loumeau	Analysis of superconducting analog-to-digital converter front-end for improved resolution and large dynamic range		ICSM	International Conference on Superconductivity and Magnetism (ICSM 2010)	Antalya, Turkey, 25-30 April 2010	
2010	V. Andrieux, M. Auguste, D.Boyer, A. Cavaillou, C. Clarke, P. Febvre, S.Gaffet, S. Henry, H. Kraus, A. Lynch, V. Mikhailik, M. McCann, E. Pozzo di Borgo, C. Sudre, G. Wavsand	Characterisation of magnetic field fluctuations at different locations within the Laboratoire Souterrain à Bas Bruit using a new SQUID prototype		iDUST	Interdisciplinary Underground Science and Technology Workshop	Apt, France (8-11 June 2010)	Published online by EDP Sciences (www.idust.org) doi: 10.1051/idust/201102003
2010	K. Tachi, M. Casse, S. Barraud, C. Dupre, A. Hubert, N. Vulliet, M.E. Faivre, C. Visioz, C. Carabasse, V. Delaye, J.M. Hartmann, H. Iwai, S. Cristoloveanu, O. Favnot, T. Ernst	Experimental study on carrier transport limiting phenomena in 10 nm width nanowire CMOS transistors		IEDM	Int. Electron Devices Meeting	San Francisco, USA (6–8 dec. 2010)	Proc. in IEDM'10 Tech. Digest, IEEE, 34.4.1–34.4.4 (2010) Art. no. 5703476
2010	G. Molas, L. Masoero, P. Blaise, A. Padovani, J. P. Colonna, E. Vianello, M. Bocquet, E. Nowak, M. Gasulla, O. Cueto, H. Grampeix, F. Martin, R. Kies, P. Brianceau, M. Gély, A. M. Papon, D. Lafond, J. P. Barnes, C. Licitra, G. Ghibaud, L. Larcher, S. Deleonibus, B. De Salvo	Investigation of the role of H-related defects in Al ₂ O ₃ blocking layer on charge-trap memory retention by atomistic simulations and device physical modelling		IEDM	IEEE IEDM 2010	San Francisco, CA, USA (Dec 2010)	IEEE Proceedings of IEDM, pp. 536-539, doi:10.1109/IEDM.2010.5703414 (2010)
2010	L. Montès et al.		Invited paper	IEEE Nano	NANO KOREA 2010 joint symposium with IEEE NANO 2010	Seoul, Korea (17-20 Aug. 2010)	Conference book.

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2010	E. Nowak, A. Hubert, L. Perniola, T. Ernst, G. Ghibaud, G. Reimbold, F. Boulanger, B. De Salvo	In-depth analysis of 3D Silicon nanowire SONOS memory characteristics by TCAD simulations		IMW	2nd International Memory Workshop	Seoul, Korea (May 2010)	
2010	F. Balestra, E. Parker, D. Leadley, H. Kurz, B. Spangenberg, M. Ostling, P.-E. Hellström, E. Sangiorgi, D. Flandre, V. Kilchvtska	NANOSIL FP7 European Network of Excellence		INC	Sixth International Nanotechnology Conference on Communications and Cooperation	Grenoble (17-20 May 2010)	
2010	F. Balestra, E. Parker, H. Kurz, M. Ostling, E. Sangiorgi, D. Flandre	Sinano Institute: European Academic and Scientific Association for Nanoelectronic		INC	Sixth International Nanotechnology Conference on Communications and Cooperation	Grenoble (17-20 May 2010)	
2010	L. Montès, B. Bercu	A gravity independent passive cooler for solar efficiency improvement		IPSC	35th IEEE Photovoltaic Specialists Conference	Honolulu, HI (20-25 Jun. 2010)	IEEE Conference Proceedings (ISSN 0160-8371)
2010	F. Domengie, J. L. Regolini, D. Bauza, and P. Morin	Impact on device performance and monitoring of a low dose of tungsten contamination by dark current spectroscopy		IRPS	IEEE Int. Reliability Physics Symposium (IRPS)	Anaheim, CA, USA (2-6 May 2009)	Proc. of IRPS 2010, pp. 259-264 (IEEE Catalog Number: CFP10RPS-CDR, ISBN: 978-1-4244-5431-0, Mai 2010)
2010	L. Negre, D. Roy, S. Boret, P. Scheer, N. Kauffmann, D. Gloria, G. Ghibaud	Impact of hot carrier stress on small signal MOSFET RF parameters		IRW	IEEE Integrated Reliability Workshop IRW 2010	Lake Tahoe, USA (Oct. 2010).	
2010	A. Zaka, P. Palestri, D. Rideau, M. Iellina, E. Dornel, Q. Rafhay, C. Tavernier, H. Jaouen	Programming efficiency and drain disturb trade-off in embedded Non Volatile Memories		IWCE	14th International Workshop on Computational Electronics	Pisa, Italy (26-29 Oct. 2010)	ISBN 978-1-4244-9383-8
2010	B. Cousin, M. Reyboz, O. Rozeau, M.A. Jaud and J. Jomaah	A Compact Model of Short Channel Effects for Undoped Cylindrical Gate-All-Around MOSFETs		IWCM	International Workshop on Compact Modeling	Taipei, Taiwan (Jan. 2010)	Proc. pp. 29-31
2010	S. Cristoloveanu	SOI trends: hot and green.	Invited paper	KCS	17th Korean Conference on Semiconductors	Daegu, Korea (24-26 feb. 2010)	XX Proc. in press
2010	S. Baudot, P. Caubet, M. Grégoire, R. A. Bianchi, R. Pantel, S. Zoll, M. Gros-Jean, R. Boujamaa, P. Normandon, C. Leroux, G. Ghibaud	Comparison of Radio Frequency Physical Vapor Deposition target material used for LaOx cap layer deposition in 32nm NMOSFETs		MAM	Int. Conf. materials for advanced metallization, MAM 2010	Malines, Belgium (March 2010)	

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2010	L. Montès, X. Xu, J. W. Lee, A. Potie, B. Bercu, T. Baron, R. Songmuang and B. Daudin	AFM Measurement of the Piezoelectric Properties of GaN and GaN/AlN/GaN Individual Nanowires		MRS	Material Research Society Spring Meeting, Symposium P: Semiconductor Nanowires - Growth, Physics, Devices, and Applications	San Francisco, USA (5-9 April 2010)	Proc. P1.10
2010	J.-P. Mazellier, J.-C. Arnault, M. Lions, F. Andrieu, R. Truche, B. Previtali, S. Saada, P. Bergonzo, S. Deleonibus, S. Cristoloveanu, O. Faynot	Study and optimization of silicon-CVD diamond interface for SOD applications.		MRS	Material Research Society Fall Meeting, Symposium J: Diamond Electronics and Bioelectronics--Fundamentals to Applications III	Boston, USA (29 Nov.-03 Dec. 2009)	Proc. J4.1
2010	H. Durou, G. A. Ardila Rodriguez, A. Ramond, X. Dollat, C. Rossi, D. Esteve	Micromachined bulk PZT piezoelectric vibration harvester to improve effectiveness over low amplitude and low frequency vibrations		PowerMEMS	POWERMEMS 2010	Louvain (Belgique), 30 Novembre - 3 december 2010	Technical Digest - Oral Sessions PowerMEMS 2010, pp, 27-30, ISBN- 13: 978-9-07380-288-9
2010	D.R. Ball, M.L. Alles, R.D. Schrimpf, S. Cristoloveanu	Comparing single event upset sensitivity of bulk vs. SOI based FinFET SRAM cells using TCAD simulations.		SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)
2010	T. Benoist, C. Fenouillet-Beranger, P. Perreau, C. Buj, P. Galy, D. Marin-Cudraz, O. Faynot, S. Cristoloveanu, P. Gentil	ESD robustness of FDSOI gated diode for ESD network design: thin or thick BOX?		SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)
2010	M. Mojarradi, S. Cristoloveanu, B. Blalock, E. Kolawa	Exploiting SOICMOS for the extreme environments of future space missions.	Invited paper	SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)
2010	S.-J. Chang, K.-I. Na, M. Bawedin, Y.-H. Bae, K.-H. Park, J.-H. Lee, W. Xiong, S. Cristoloveanu	Investigation of hysteresis memory effects in SOI FinFETs with ONO buried insulator.		SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)
2010	W. Van Den Daele, C. Le Royer, E. Augendre, G. Ghibaudo, S. Cristoloveanu	Novel characterization of fully-depleted GeOI pMOSFET by magnetoresistance.		SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)

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2010	R. Ritzenthaler, F. Lime, M. Ricoma, F. Martinez, O. Faynot, F. Pascal, M. Valenza, E. Miranda, S. Cristoloveanu, B. Iniguez	Parasitic back-interface conduction in planar and triple-gate SOI transistors.		SOI Conf	2010 IEEE International SOI Conference	San Diego, California, USA (11-14 oct. 2010)	2010 IEEE Conference Proceedings (ISSN 1078-621X)
2010	Cuiqin Xu, P. Batude, C. Rauer, C. Le Royer, L. Hutin, A. Pouydebasque, C. Tabone, B. Previtali, O. Faynot, M. Mouis, M. Vinet	Ion-loff performance analysis of FDSOI MOSFETs with low processing temperature		SSDM	International Conference on Solid State Devices and Materials (SSDM)	Tokyo, Japan (22-24 Sept. 2010)	Conference book.
2010	J.-L. Huguenin, S. Monfray, G. Bidal, S. Denorme, P. Perreau, N. Loubet, Y. Campidelli, M. P. Samson, C. Arvet, K. Benotmane, F. Leverd, P. Gouraud, B. Le-Gratiet, C. De-Butet, L. Pinzelli, R. Beneyton, S. Barnola, T. Morel, A. Halimaoui, F. Boeuf, G. Ghibaudo, T. Skotnicki	Ultra-Thin (4nm) Gate-All-Around CMOS devices with High-k/Metal for Low Power Multimedia Applications		SSDM	International Conference on Solid State Devices and Materials (SSDM)	Tokyo, Japan (22-24 Sept. 2010)	
2010	K-H. Park, M. Bawedin, J. H. Lee, Y-H. Bae, K-I. Na, S. Cristoloveanu	A new fully depleted double-gate MSDRAM cell with added nonvolatile functionality.		ULIS	Int. Conference on Ultimate Integration on Silicon (ULIS'10)	Glasgow, Scotland (18-19 mars 2010)	Proc. in ULIS 2010, 97-100 (2010)
2010	Q. Rafhay, R. Clerc, J. Coignus, G. Pananakakis and G. Ghibaudo	Dark Space, Quantum Capacitance and Inversion Capacitance in Si, Ge, GaAs and In _{0.53} Ga _{0.47} As nMOS Capacitors		ULIS	Int. Conference on Ultimate Integration of Silicon	Glasgow, UK (17-19 March 2010)	Proceeding of ULIS 2010

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2010	J.-L. Huguenin, S. Monfray, G. Bidal, S. Denorme, P. Perreau, S. Barnola, M.-P. Samson, C. Arvet, K. Benotmane, N. Loubet, Q. Liu, Y. Campidelli, F. Leverd, F. Abbate, L. Clement, C. Borowiak, A. Cros, A. Bajolet, S. Handler, D. Marin-Cudraz, T. Benoist, P. Galy, C. Fenouillet-Beranger, O. Faynot, G. Ghibaudo, F. Boeuf, T. Skotnicki	Hybrid Localized SOI/Bulk technology for Low Power System-on-Chip.		VLSI Symposium	IEEE VLSI symposium 2010	Hawaii, USA (June 2010)	
2010	J.-L. Huguenin, S. Monfray, S. Denorme, G. Bidal, P. Perreau, S. Barnola, M.-P. Samson, K. Benotmane, N. Loubet, Y. Campidelli, F. Leverd, F. Abbate, L. Clement, C. Borowiak, Dominique Golanski, C. Fenouillet-Beranger, F. Boeuf, G. Ghibaudo, T. Skotnicki	Localized SOI Logic and Bulk I/O devices co-integration for Low Power System-on-Chip Technology.	Best student paper	VLSI-TSA	International Symposium on VLSI Technology, Systems and Applications (VLSI-TSA)	Taiwan (April 2010)	
2010	B. Cousin, M. Reyboz, O. Rozeau, M.A. Jaud, T. Ernest and J. Jomaah	A Continuous Compact Model of Short-Channel Effects for Undoped Cylindrical Gate-All-Around MOSFETs		WCM	Workshop on Compact Modeling	Anaheim, CA, USA (June 2010)	
2010	J. M. Olchowik, K. Cieslak, S. Gulkowski, A. Kaminski, A. Fave	Analysis of internal reflectivity of silicon ELO PV cells obtained by LPE		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	S. Tutashkonko, A. Kaminski-Cachopo, C. Boulord & M. Lemiti	Copper Light Induced Plating on Silver Screen-Printed Contacts of Silicon Solar Cells		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	G. Gomard, E. Drouard, O. El Daif, X. Meng & C. Seassal, A. Kaminski-Cachopo, A. Fave & M. Lemiti	Design and Simulation of 2D Photonic Crystal Thin Film Photovoltaic, Cells		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.

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2010	O. El Daif, G. Gomard, X. Meng, E. Drouard, A. Kaminski-Cachopo, A. Fave	Fabrication and Characterisation of Photonic Crystal Amorphous Silicon Photovoltaic Cells		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	C. Boulord, G. Poulain, A. Kaminski-Cachopo, D. Blanc-Péllissier & M. Lemiti, Y. Veschetti & D. Heslinga	Optimization of Electroplating Contacts for Front Side Silicon Solar Cells Metallization		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	R. Cabal, N. Auriac, B. Grange, Y. Veschetti, A. Kaminski, D. Heslinga	Process integration of boron BSF by CVD technique on large surface in bifacial solar cell process flow		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	A. Fave, A. Kaminski-Cachopo, Y. Park, S. Tutashkonko & M. Lemiti, A. Slaoui	Realisation of Self-Aligned Thin Film Si Solar Cell with Interdigitated Structure		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	G. Poulain, C. Boulord, D. Blanc-Péllissier, A. Kaminski-Cachopo & M. Lemiti, M. Gauthier	Towards a Self-Aligned Process for Selective Emitters on Silicon Solar Cells		WCPEC	5th World Conference on Photovoltaic Energy Conversion	Valencia, Spain (6-10 Sept. 2010)	Proc. of the 5th WCPEC, pp.
2010	O. Engström, F. Ducroquet, B. Raessi, J. Schubert, JMJ Lopes	Capture cross sections for holes at LaLuO/Si interfaces		WODIM	16th Workshop on Dielectric Materials	Bratislava, Slovaquia (28-30 June 2010)	Proc. 16th WODIM, 2010
2010	E. Rauwel, P. Rauwel, F. Ducroquet, I. Matko, A. Lourenço	Metallic oxygen barrier diffusion applied to high-k deposition		WODIM	16th Workshop on Dielectric Materials	Bratislava, Slovaquia (28-30 June 2010)	Proc. 16th WODIM, 2010
2010	J. Jomaah, K. Bennamane, F. Balestra, G. Ghibaudo	Low temperature characterization of different deep submicron SOI and FinFET devices		WOLTE	9th Int. Workshop on Low Temperature Electronics, WOLTE 9	Guaruja, Brazil (21-23 June 2010).	Proc. pp. 19-22
2010	Subramanian N, G.Ghibaudo, M. Mouis, G. Bidal, F. Boeuf	Low Temperature Characterization of FDSON MOSFETs		WOLTE	9th Int. Workshop on Low Temperature Electronics, WOLTE 9	Guaruja, Brazil (21-23 June 2010).	Conference Proceedings, pp. 75-78 (June 2010)
2010	P. Martin, A.S. Royet and G. Ghibaudo	MOS Transistor Matching at Low Temperature for Analog Circuit Design		WOLTE	9th Int. Workshop on Low Temperature Electronics, WOLTE 9	Guaruja, Brazil (21-23 June 2010).	
2010	P. Martin, A.S. Royet, M. Cavelier, R. Fascio and G. Ghibaudo	Several Issues for Analog Design with a 0.18 µm CMOS Technology at Low Temperature		WOLTE	9th Int. Workshop on Low Temperature Electronics, WOLTE 9	Guaruja, Brazil (21-23 June 2010).	

Année	Auteurs	Titre		Sigle	Conférence	Lieu, date	Actes
2010	C. Boulord, A. Kaminski, Y. Veschetti, D. Blanc-Pelissier, B. Grange, A. Bettinelli, D. Helsingans M. Lemiti	Optimization of electroless nickel plating for front side silicon solar cells metallization		Workshop on Metallization	2nd Workshop on Metallization for Crystalline Silicon Solar Cells	Konstanz, Germany (14-15 April 2010)	Proceedings of 2nd Workshop on Metallization